

TiSi₂ and LIFT as potential alternatives to silver and screen printing for solar cells electric contacts



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Metallization & Interconnection
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ABSTRACT: Titanium disilicide (TiSi₂) deposited by Laser-Induced Forward Transfer (LIFT) shows promising characteristics to replace the current silver screen-printing process for the formation of the crystalline silicon solar cells' electrode [1,2,3]. In this work, an exhaustive analysis of the **main parameters influencing the deposition process** of titanium (Ti) fingers through LIFT such as laser wavelength, frequency, power or scanning speed, has been carried out. Continuous Ti deposited lines with a width of tens of μm have been obtained with a specific set of process parameters through LIFT process and after a rapid thermal processing **TiSi₂ material has been formed**. The resistivity of the TiSi₂ material decreased 2.9 times with respect to Ti alone, which is in good agreement with the literature and confirms the formation of TiSi₂ in its most conductive C54 phase [4,5]. Taking into account cost differences between silver and Ti, this material, with **a conductivity in the order of 10⁶ S/m, shows a good potential** to be an alternative on a specific design of the electrode -number of fingers and busbars, thicknesses and widths, etc. [2].

Keywords: Metallization, titanium, titanium silicide, LIFT.

1. MOTIVATION

- Currently, **silver** is the material that introduces **the most price and supply risk** to the broad development of PV production so further work is needed in the PV community to replace it with more abundant metals [6].
- The **titanium silicide** material has been known for about four decades in the microelectronics industry, providing interesting conductivity properties, compatibility with crystalline Si technology and low contact resistances [7].
- Furthermore, the **LIFT direct printing process is a flexible, versatile and gentle process** which does not require direct pressure on the substrate, which will be a necessary requirement when evolving to thinner crystalline silicon wafers [3].

The combination of LIFT and TiSi₂ shows promising characteristics to replace the current silver screen-printing process to form the electrode of crystalline silicon solar cells and could be a **breakthrough in the search for new materials and processes in the rapidly evolving photovoltaic technology**.

2. LIFT PROCESS

In the LIFT process, a **thin film is initially deposited** onto a donor substrate transparent to a laser radiation. Then it is placed facing a receiver substrate and a **laser beam is focused on the interface, transferring the affected material** from the thin film. In this work, glass slides have been used as donor substrates, where Ti thin films have been deposited by sputtering, and monocrystalline silicon wafers -both polished and textured- as receiver substrates.

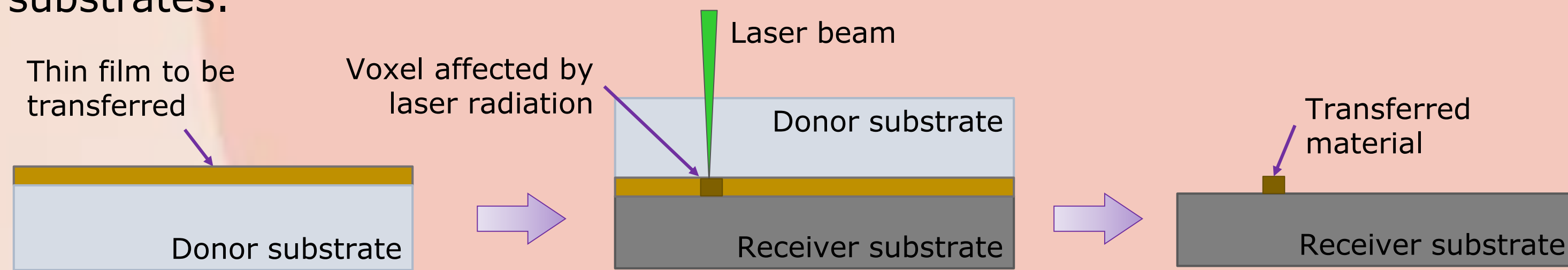


Fig. 1. Schematic of the LIFT process

3. TITANIUM DEPOSITION

Multiple experiments have been carried out **to find the optimal conditions**, using **infrared and green pulsed lasers**, with 1064 and 532 nm of wavelength respectively, and **tuning pulse power** through diodes' current (from 10 to 40 A), **frequency** (from 2 to 100 kHz) and **scanning speed** (from 300 to 1400 mm/s). Optimal parameters for this specific process have been found to be **532 nm, 20 A, 10 kHz and 300 mm/s**.

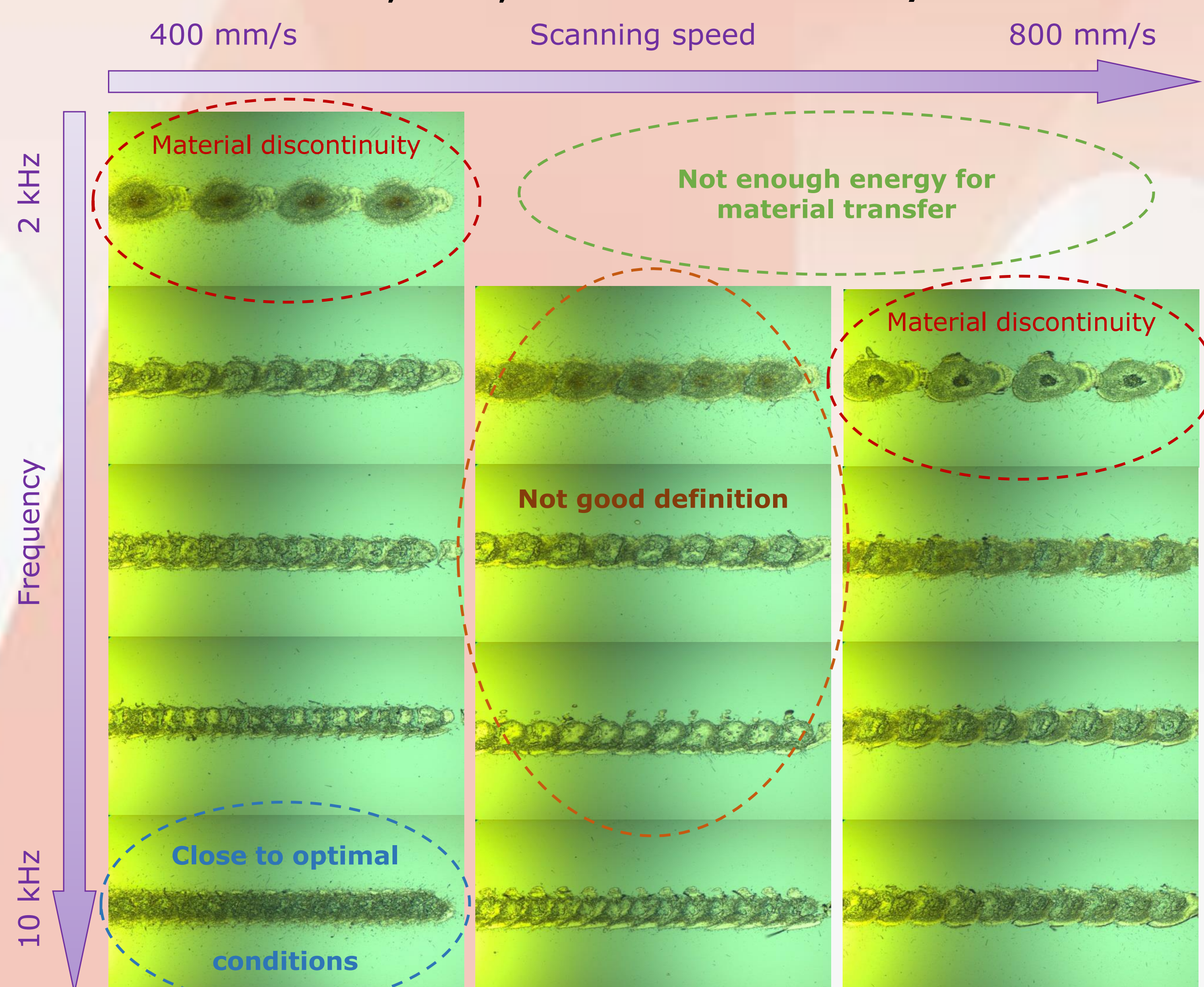


Fig. 2. Example of matrix of experiments used for morphological characterization

4. TiSi₂ FORMATION

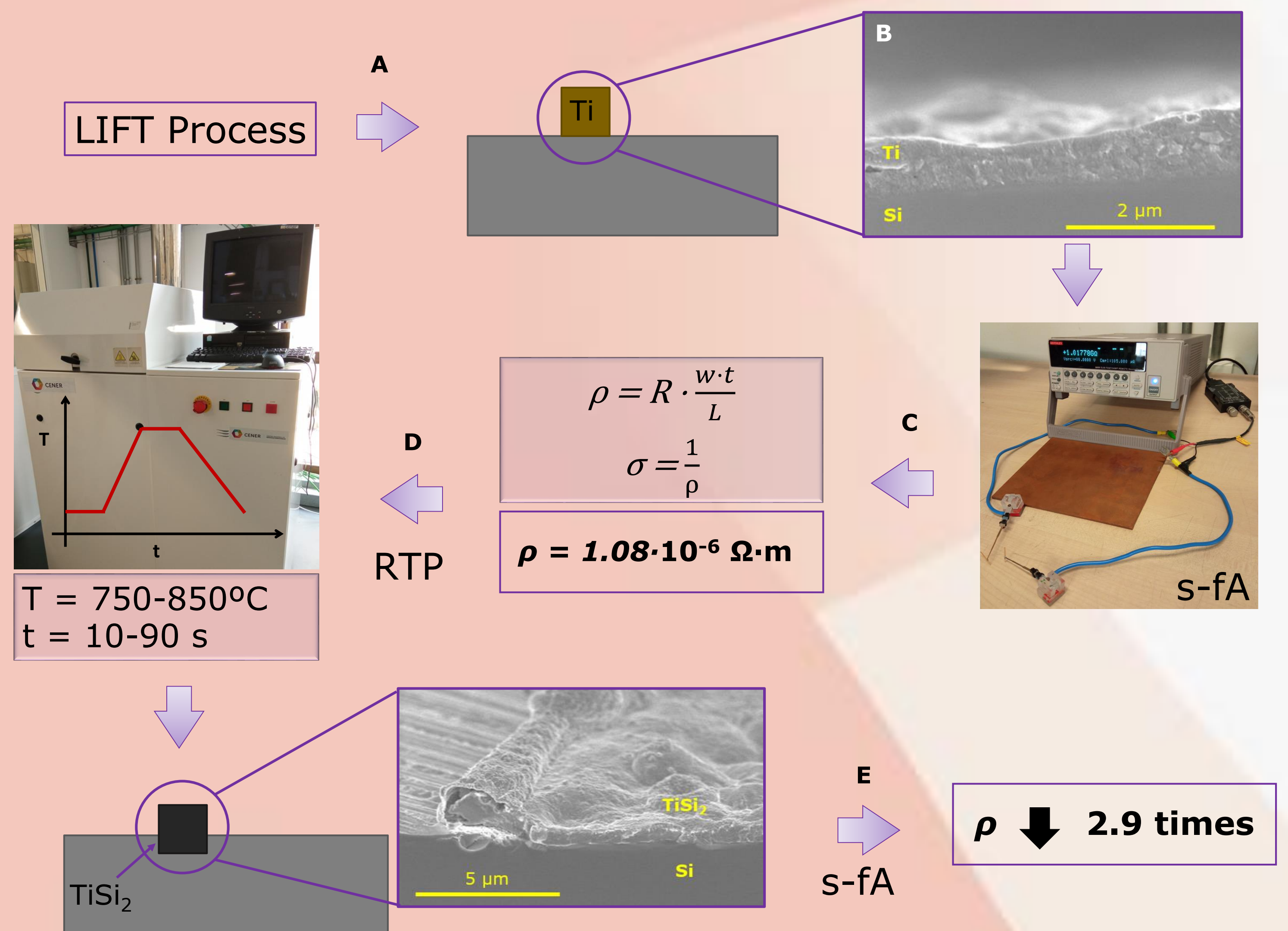


Fig. 3. Workflow followed in this research

Once the **Ti line or finger** has been deposited on the Si wafer by LIFT (A), its **width (w) and thickness (t) have been measured** (B) by means of scanning electron microscopy (SEM) and its electrical resistance (R) has been characterized using a sub-femtoamp (s-fA) meter (C).

Fingers used for this characterization have 4 cm of length (L), 100 μm of w and 600 nm of t. According to equations of C, **resistivity (ρ)** have been calculated. Then, Ti fingers have been rapidly thermally **annealed** (D, RTP). During this process, **Ti reacts with Si from the substrate to form TiSi₂**.

To check this formation, fingers have been electrically characterized again (E). Annealing at 800°C during 30 s, a **reduction of 2.9 times in ρ** has been obtained, which is in good agreement with the literature and confirms the formation of TiSi₂ in its **most conductive C54 phase** [4,5].

Fig. 4 shows a picture of a **Ti electrode**, including **fingers and busbars, deposited by LIFT** on the silicon nitride antireflective (AR) layer as a proof of concept.

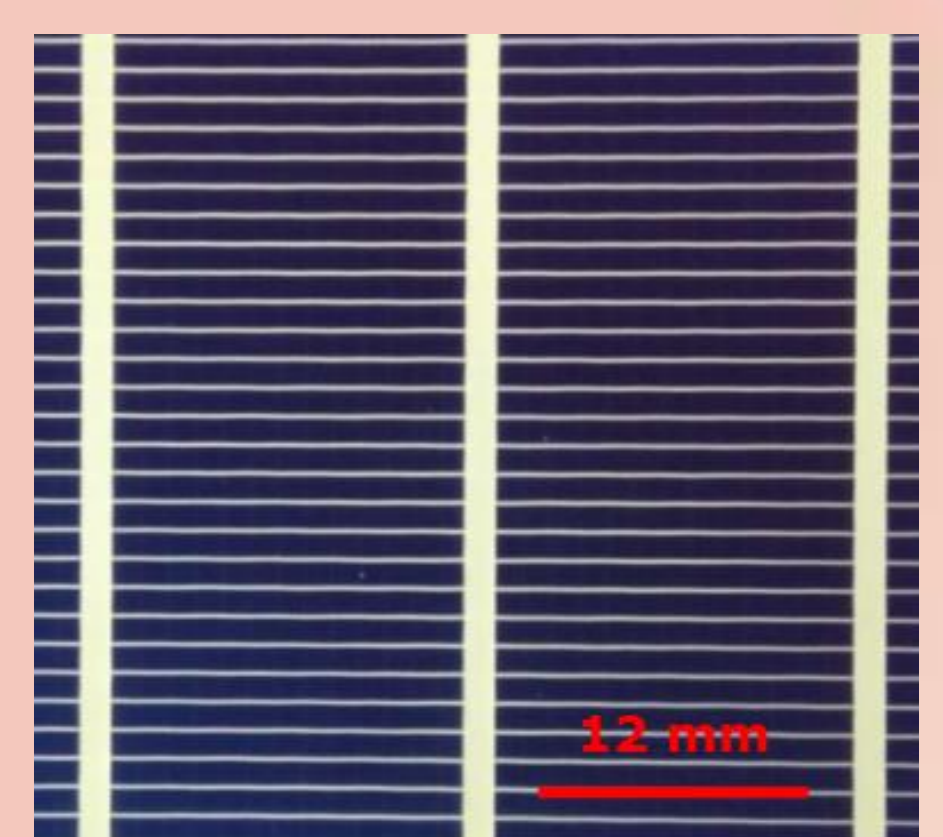


Fig. 4. Picture of a Ti electrode

5. CONCLUSIONS & FUTURE WORK

- LIFT deposited continuous Ti fingers** have been demonstrated adjusting process parameters.
- After a thermal annealing process on these Ti fingers, **C54 TiSi₂ fingers have been obtained** joined with a decrease in conductivity compared to Ti deposited fingers.
- Future work will be devoted to explore the way to get Ti in contact with the Si of the substrate through the AR layer, to deposit **TiSi₂ C54 lines directly by LIFT** without the need of an additional high temperature process step, and to check **final performance** on state of the art crystalline silicon solar cells.

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